



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of:)
Shunpei YAMAZAKI) Examiner: Remmon R. Forde
Serial No.: 10/079,512) Group Art Unit: 2826
Filed: February 22, 2002)
For: SEMICONDUCTOR DEVICE)

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
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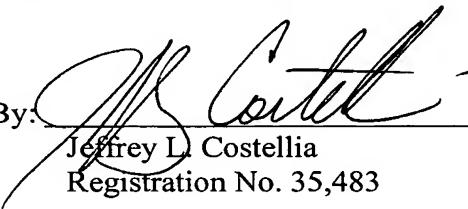
Sir:

In accordance with the duty of disclosure as set forth in 37 C.F.R. §1.56, Applicants hereby submit the following information in conformance with 37 C.F.R. §§ 1.97 and 1.98. Pursuant to 37 C.F.R. § 1.98, a copy of each of the documents cited is enclosed.

It is requested that the accompanying PTO-1449 be considered and made of record in the above-identified application. To assist the Examiner, the documents are listed on the attached form PTO-1449. It is respectfully requested that an Examiner initial a copy of this form be returned to the undersigned.

The Commissioner is hereby authorized to charge any fees connected with this filing which may be required now, or credit any overpayment to Deposit Account No. 19-2380 (740756-2441).

Respectfully submitted,

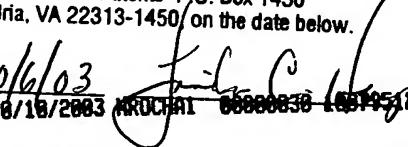
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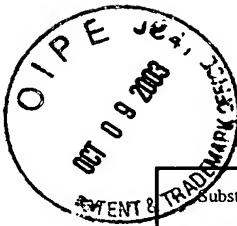
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10/16/2003 ARD/CHAI 06000038 10074542

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 Substitute for form 1449A/PTO				<i>Complete if Known</i>	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Application Number	10/079,512
				Filing Date	February 22, 2002
				First Named Inventor	Shunpei YAMAZAKI
				Art Unit	2826
				Examiner Name	Remmon R. Forde
Sheet	1	of	2	Attorney Docket Number	740756-2441

U.S. PATENT DOCUMENTS

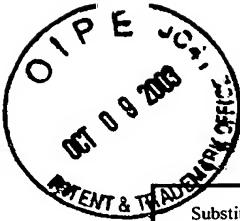
Examiner Initials*	Cite No. ¹	U.S. Patent Document	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number - Kind Code ² (if known)			
		US-4,851,363	07-25-1989	Troxell et al.	
		US-5,217,910	06-08-1993	Shimizu et al.	
		US-5,323,042	06-21-1994	Matsumoto	
		US-5,413,945	05-09-1995	Chien et al.	
		US-5,528,397	06-18-1996	Zavracky et al.	
		US-5,532,176	07-02-1996	Katada et al.	
		US-5,583,369	12-10-1996	Yamazaki et al.	
		US-5,643,826	07-01-1997	Ohtani et al.	
		US-5,686,328	11-11-1997	Zhang et al.	
		US-5,705,424	01-06-1998	Zavracky et al.	
		US-5,736,750	04-07-1998	Yamazaki et al.	
		US-5,830,787	11-03-1998	Kim	
		US-5,923,962	07-13-1999	Ohtani et al.	
		US-5,949,107	09-07-1999	Zhang	
		US-6,030,667	02-29-2000	Nakagawa et al.	
		US-6,114,715	09-05-2000	Hamada	
		US-6,166,414	12-26-2000	Miyazaki et al.	
		US-6,198,133 B1	03-06-2001	Yamazaki et al.	
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		US-6,281,552 B1	08-28-2001	Kawasaki et al.	

FOREIGN PATENT DOCUMENTS

Examiner Signature		Date Considered	
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Applicant's unique citation designation number (optional). ² See *Kinds Codes of USPTO Patent Documents* at 222.uspto.gov or MPEP 901.04. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.



Substitute for form 1449A/PTO				<i>Complete if Known</i>	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT <i>(use as many sheets as necessary)</i>				Application Number	10/079,512
Sheet	2	of	2	Filing Date	February 22, 2002
				First Named Inventor	Shunpei YAMAZAKI
				Art Unit	2826
				Examiner Name	Remmon R. Forde
				Attorney Docket Number	740756-2441

FOREIGN PATENT DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Application of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Country Code ³	Number ⁴ <i>(if known)</i>			
		JP	04-258160	09-14-1992	Miyake	Abstract
		JP	04-369271	12-22-1992	Takeda et al.	Full
		JP	05-102483	04-23-1993	Ueda	Full
		JP	06-148685	05-27-1994	Nakazaono et al.	Full
		JP	07-130652	05-19-1995	Ohtani et al.	Abstract
		JP	07-235680	09-05-1995	Goto et al.	Full
		JP	08-078329	03-22-1996	Ohtani	Abstract
		JP	08-264784	10-11-1996	Kurokawa	Abstract
		JP	08-274336	10-18-1996	Uemoto et al.	Full
		JP	09-191111	07-22-1997	Zhang	Abstract
		JP	09-293600	11-11-1997	Nakagawa et al.	Abstract
		JP	10-104659	04-24-1998	Nakajima et al.	Abstract
		JP	10-135468	05-22-1998	Yamazaki et al.	Abstract
		JP	10-135469	05-22-1998	Yamazaki et al.	Abstract
		JP	10-233511	09-02-1998	Seto	Full
		JP	10-294280	11-04-1998	Yamazaki et al.	Abstract
		JP	11-191628	07-13-1999	Yamazaki et al.	Abstract
		JP	11-345767	12-14-1999	Yamazaki et al.	Abstract
		JP	11-354442	12-24-1999	Ohtani et al.	Abstract
		JP	60-127761	07-08-1985	Fuse	Abstract

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS						
Examiner Initials ¹	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.				T ²
		HATANO ET AL., "A NOVEL SELF ALIGNED GATE-OVERLAPPED LDD POLY-SI TFT WITH HIGH RELIABILITY AND PERFORMANCE", IEDM 1997, PP. 523-526				/
		SHIMOKAWA ET AL., "CHARACTERIZATION OF HIGH-EFFICIENCY CAST-SI SOLAR CELL WAFERS BY MBIC MEASUREMENT", JAPANESE JOURNAL OF APPLIED PHYSICS, VOL. 27, NO. 5, MAY 1988, PP. 751-758				/

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